Journal	Instrument	YEAR	Ref
Semiconductor Science and Technology	IMS Wf	2025	Trench Super junction power device by plasma doping: A Structural, Chemical-Physical, and Profiling Investigation. C. Galati, N. Spinella, C. L. Liao, G. Anastasi, C. Bongiorno, P. Fiorenza, M. Italia, V. C. Ngwan and L. Renna. Clelia Galati et al 2025 Semicond. Sci. Technol. in press https://doi.org/10.1088/1361-6641/ae1381
Vacuum	IMS Wf	2025	Reduction of TiO2 - titanium dioxide (anatase-rutile) with a hydrogen-rich plasma produced by an Electron Cyclotron Wave Resonance source. Marko Sikirić, Patrick Choquet, Adrian-Marie Philippe, Nathalie Valle, Kathryn Hadler, Simon Bulou. Vacuum, Volume 244, Part B, 2026, 114952, ISSN 0042-207X, https://doi.org/10.1016/j.vacuum.2025.114952
Materials Science in Semiconductor Processing	IMS Wf	2026	Influence of strain and initial reactions on epitaxial SiGe growth. Yuji Yamamoto, Wei-Chen Wen, Florian Bärwolf, Jon Schlipf, Oksana Fursenko, Sushil Karki, Marvin H. Zoellner, Junichi Murota, Bernd Tillack. Materials Science in Semiconductor Processing, Volume 209, 2026, 110572, ISSN 1369-8001, https://doi.org/10.1016/j.mssp.2026.110572
Science	SC Ultra	2025	Order-to-disorder transition due to entropy in layered and 2D carbides. Brian C. Wyatt, Yinan Yang, Paweł P. Michałowski, Tetiana Parker, Yamilée Morency, Francesca Urban, Givi Kadagishvili, Manushree Tanwar, Sixbert P. Muhoza, Srinivasa Kartik Nemani, Annabelle Bedford, Hui Fang, Zachary D. Hood, Junwoo Jang, Krutarth Kamath, Bethany G. Wright, Rebecca Disko, Anupma Thakur, Sanguk Han, Neil Ghosh, Xianfan Xu, Zahra Fakhraai, Yury Gogotsi, Aleksandra Vojvodic, De-en Jiang, Babak Anasori. Science 4 Sep 2025, Vol 389, Issue 6764, pp. 1054-1058, DOI: 10.1126/science.adv4415
Surface and Coatings Technology	SC Ultra	2025	Study of anatase TiO_2 growth mechanisms via pulsed Electron Cyclotron Wave Resonance plasma at low substrate temperature. Benjamin Dey, Patrick Choquet, Nathalie Valle, Mireille Richard-Plouet, Agnès Granier, Simon Bulou. Surface and Coatings Technology, Volume 516, 2025,132759, ISSN 0257-8972, https://doi.org/10.1016/j.surfcoat.2025.132759
Materials & Design	SC Ultra	2025	Influence of welding-induced microstructure on fatigue crack growth in 5xxx aluminum alloys in air and hydrogen environments, Mahdieh Safyari, Mansoob Ahmad, Jean-Nicolas Audinot, Antje Biesemeier, Masoud Moshtaghi, Materials & Design, 2025, 115220, ISSN 0264-1275, https://doi.org/10.1016/j.matdes.2025.115220
Vacuum	SC Ultra	2026	Improvement of carbon depth profiling within shallow structures by secondary ion mass spectrometry (SIMS). A. Merkulov, A. Franquet, R. Tilmann. Vacuum, Volume 244, Part A, 2026, 114893, ISSN 0042-207X, https://doi.org/10.1016/j.vacuum.2025.114893
Chem. Mater	SC Ultra	2026	Understanding the Effect of Oxygen on M5AX4 Structure, Stability, and Mechanical Properties. Marley Downes, Martin Dahlqvist, Paweł Piotr Michałowski, Johanna Rosen and Yury Gogotsi. Chem. Mater. XXXX, XXX, XXX−XXX. https://doi.org/10.1021/acs.chemmater.5c02254
Journal of the American Ceramic Society	SC Ultra	2026	On the asymmetry of soda lime silicate float glass structure and chemistry. Mattia Biesuz, Levent Karacasulu, Michele Cassetta, Mario Barozzi, Roberto Canteri, Maciej Oskar Liedke, Eric Hirschmann, Andreas Wagner, Sebastiano Mariazzi, Gian D. Sorarù, Vincenzo M. Sglavo, Roberto S. Brusa. Journal of the American Ceramic Society. https://doi.org/10.1111/jace.70488
Nature Synthesis	SC Ultra	2026	Triphasic synthesis of MXenes with uniform and controlled halogen terminations. Li, D., Zheng, W., Ghorbani-Asl, M. et al. Nat. Synth (2026). https://doi.org/10.1038/s44160-025-00970-w
AIP Advances	SC Ultra	2026	Enhancing Cu-barrier properties of 2D-WS2 barriers: The role of grain size and surface passivation. Salim El Kazzi, Vejay Girija Jagadeesan; Ivan Erofeev ; Sergej Pasko ; Simonas Krotkus ;Paweł Piotr Michałowski ; Chandan Das ; Utkur Mirsaidov. AIP Advances 16, 015127 (2026). https://doi.org/10.1063/5.0292715.
The Journal of Physical Chemistry C	SC Ultra	2026	Band-like Optical Signatures of Ti3C2Tx Mxenes. Hui FangZhenyao FangAnupma ThakurVahid RadNithin Chandran Balachandran SajithaPaweł P. MichałowskiMasoud SoroushBabak Anasori, Andrew M. Rappe, Zahra Fakhraai. J. Phys. Chem. C 2026, XXXX, XXX, XXX-XXX. https://doi.org/10.1021/acs.jpcc.5c08501
Inorganic Chemistry	SC Ultra	2026	Synthesis of (V0.2Cr0.8)2(Ga0.5Ge0.5)(C0.6N0.4), a Triple-Site Solid Solution MAX Phase. Isabel Huck, Niels Kubitza, Tom Keil, Marius Schlapp, Robert Winkler, Prajna Bhatt, Christoph Schlueter, Pardeep K. Thakur, Tien-Lin Lee, Paweł P. Michałowski, Leopoldo Molina-Luna, Anna Regoutz, Christina S. Birkel. norg. Chem. 2026, 65, 6, 3665–3672. https://doi.org/10.1021/acs.inorgchem.5c05814

Crystal Growth & Design	SC Ultra	2026	Suppressing Oxygen Incorporation in III–V Aluminum-Containing Alloys in Metal Organic Vapor Phase Epitaxy by Antimony as a Surfactant. Ayse Ozcan-Atar, Pawel P. Michalowski, Agnieszka Gocalinska, John O'Hara, Luca Colavecchi, Gediminas Juska, Emanuele Pelucchi. Cryst. Growth Des. 2026, XXXX, XXX, XXX-XXX. https://doi.org/10.1021/acs.cgd.5c01580
Applied NanoMaterials	SC Ultra	2026	Engineering Disordered Metallic Carbonaceous Materials: A Protocol for the Synthesis via Graphene Edge Hydrolysis. Katarzyna Donato, Gavin Kok WaiKoon, Sarah Lee, Alexandra Carvalho, HuiLi Tan, Mariana Costa, Paweł Piotr Michałowski, Zuzana Němečková, Petra Ecorchard, Ricardo K.Donato, and Antonio Castro Neto. ACS Appl. Nano Mater. 2026,9,4699−4714. https://pubs.acs.org/doi/pdf/10.1021/acsanm.6c00047?ref=article_openPDF
J. Vac. Sci. Technol	SC Ultra	2026	Orbitrap™-SIMS for accurate quantification of arsenic in SiGe across blanket and fin-type geometries. Rita Tilmann, Alexander Pirkl, AlexisFranquet, AlexandreMerkulov, and Paul van der Heide. J. Vac. Sci. Technol. A 44(3) May/Jun 2026; doi: 10.1116/6.0005245
Science AdvAnceS	SC Ultra	2026	Triggering avalanche- like ultraviolet photomultiplication phenomena in ultrathin amorphous/crystalline gallium nitride heterostructures. Dongyang Luo, Haochen Zhang, Yong Yan, Wei Chen, Danhao Wang, Huabin Yu, Xin Liu, Yang Kang, Muhammad Hunain Memon, Zhixiang Gao, Yuanmin Luo, Si Liu, Wengang Gu, Boon S. Oo2, Lan Fu, Sheng Liu, Haiding Sun. Sci. Adv. 12, eaea7319 (2026)
Vacuum	SC Ultra	2025	ICP-RIE etching of MESA and trench SiC structures in SF6 + O2 plasma: significant difference in SiC etching rate dependence on oxygen content. K. Racka-Szmidt, J. Żelazko, P.P. Michałowski, A. Roguska, M. Pisarek, A. Banasiak, K. Przyborowska, B. Stańczyk, A. Harmasz, M. Sochacki. Vacuum, Volume 240, 2025,114543, ISSN 0042-207X, https://doi.org/10.1016/j.vacuum.2025.114543
chemrxiv	SC Ultra	2025	Protocol and dataset for the synthesis and characterization of disordered metallic carbon materials from graphene edge hydrolysis. Katarzyna Z. Donato, Gavin K. W. Koon, Sarah J. Lee, Alexandra Carvalho, Hui Li Tan, Mariana, C. F. Costa, Paweł P. Michałowski, Jakub Tolasz, Petra Ecorchard, Ricardo K. Donato, A. H. Castro Neto. https://doi.org/10.26434/chemrxiv-2024-h3pkk-v2 ORCID
Applied Surface Science	SC Ultra	2025	Secondary ion mass spectrometry measurements with a large scale-to-resolution ratio. Paweł Piotr Michałowski. https://doi.org/10.1016/j.apsusc.2025.163272
arxiv	SC Ultra	2025	Sub-micron Cu(In,Ga)Se2 solar cell with efficiency of 18.2% enabled by a hole transport layer. Taowen Wang, Longfei Song, Saeed Bayat, Michele Melchiorre, Nathalie Valle, Adrian Marie Philippe, Emmanuel Defay, Sebastjan Glinsek, Susanne Siebentritt. https://arxiv.org/pdf/2505.03253
Polymer	SC Ultra	2025	Suppression of iron oxidation problem into PVDF/PMMA composites with ceramic additives: SiO2 vs. TiO2. Sylwia Kozdra, Michiko Atsumi, Małgorzata Możdżonek, Agnieszka Grabias, Agnieszka Malinowska, Adrianna Rejmer, Paweł Piotr Michałowski. Polymer, Volume 320, 2025, 128100, ISSN 0032-3861, https://doi.org/10.1016/j.polymer.2025.128100
ECS Journal of Solid State Science and Technology	SC Ultra	2025	Epitaxial Si/SiGe Multi-Stacks: From Stacked Nano-Sheet to Fork-Sheet and CFET Devices. R. Loo,z A. Akula,Y. Shimura, C. Porret, E. Rosseel, T. Dursap,A. Y. Hikavyy,a M. Beggiato, J. Bogdanowicz, A. Merkulov, M. Ayyad, H. Han, O. Richard, A. Impagnatiello, D. Wang,K. Yamamoto, T. Sipőcz,Á. Kerekes, H. Mertens, N. Horiguchi and R. Langer. ECS Journal of Solid State Science and Technology, 2025 14 015003. 10.1149/2162-8777/ada79f
Applied Surface Science	SC Ultra	2025	Why 'Zn diffusion' is not always diffusion: Surface physics and a 40-year-old epitaxy problem Ayse Ozcan-Atar, Agnieszka Gocalinska, Paweł P. Michałowski, Mack Johnson, John O'Hara, Brian Corbett, Adrianna Rejmer, Frank Peters, Dimitri D. Vvedensky, Andrew Zangwill, Gediminas Juska, Emanuele Pelucchi. Applied Surface Science, 2025, 162360, ISSN 0169-4332,chttps://doi.org/10.1016/j.apsusc.2025.162360
Materials Science in Semiconductor Processing	SC Ultra	2025	Solid-phase epitaxial regrowth of phosphorus-doped silicon by nanosecond laser annealing. S. Kerdil`es, M. Opprecht, D. Bosch, M. Ribotta, B. Skl´enard, L. Brunet, P.P. Michalowski. Materials Science in Semiconductor Processing Volume 186, February 2025, 109043. https://doi.org/10.1016/j.mssp.2024.109043
J. Vac. Sci. Technol. B	SC Ultra	2025	Ultralow impact energy dynamic secondary ion mass spectrometry with nonfully oxidizing surface conditions. A. Merkulov. J. Vac. Sci. Technol. B 42, 064005 (2024).
Applied Surface Science	SC Ultra	2025	Origin of ion bombardment induced Tb oxidation in Tb/Co multilayers. Daniel Kiphart, M Krupiński, Marzena Mitura-Nowak, Paweł Piotr Michałowski, Mateusz Kowacz, Marek Schmidt, Feliks Stobiecki, Gabriel David Chaves-O'Flynn, Piotr Kuświk. Applied Surface Science 685,162090 (2025).

Materials Science in Semiconductor Processing	SC Ultra	2024	Thickness and Mg doping of graded AlGaN layers: Influence on contact layer's structural and electrical properties for DUV emitters. Dominika Majchrzak, Lan Maria Tran, Michał Babij, Jarosław Serafińczuk, Wojciech Olszewski, Rafał Kuna, Katarzyna Opołczyńska, Adrianna Piejko, Paweł Piotr Michałowski, Robert Kudrawiec, Detlef Hommel. Materials Science in Semiconductor Processing 178,108452 (2024). https://doi.org/10.1016/j.mssp.2024.108452
Carbon	SC Ultra	2024	Unraveling the role of boron dimers in the electrical anisotropy and superconductivity in boron-doped diamond, Michał Sobaszek, Soonho Kwon, Tomasz Klimczuk, Paweł P Michałowski, Jacek Ryl, Bogdan Rutkowski, Dongying Wang, Xinwei Li, Marc Bockrath, Robert Bogdanowicz, William A Goddard III. Carbon 228,119337 (2024). https://doi.org/10.1016/j.carbon.2024.119337
Measurement	SC Ultra	2024	Artifact-free secondary ion mass spectrometry profiling of a full vertical cavity surface emitting laser structure. Paweł Piotr Michałowski, Marcin G˛ebski, Patrycja Spiewak, Walery Kołkowski, Iwona Pasternak, Weronika Głowadzka, Michał Wasiak, Tomasz Czyszanowski, Włodzimierz Strupinski. MEASUR 114003. https://doi.org/10.1016/j.measurement.2023.114003
Scripta Meteriala	SC Ultra	2024	Dispersion and incorporation of TiO2 and SiC nano-particles in SAC alloy: SIMS and DFT study. Balázs Illés, Paweł Piotr Michałowski, Agata Skwarek, Halim Choi, Jaeduk Byun, Karel Dušek, David Bušek, Adrian Pietruszka. Scripta Materialia, Volume 243, 2024, 115987, ISSN 1359-6462. https://doi.org/10.1016/j.scriptamat.2024.115987.
Applied Surface Science	SC Ultra	2024	Selective etching of multilayer graphene with ultra-low impact energy oxygen ions, Paweł Piotr Michałowski, Applied Surface Science, Volume 655, 2024, 159591, ISSN 0169-4332, https://doi.org/10.1016/j.apsusc.2024.159591
Applied Materials & Interfaces	SC Ultra	2024	TiO2/PDA Multilayer Nanocomposites with Exceptionally Sharp Large-Scale Interfaces and Nitrogen Doping Gradient. Jakub Szewczyk, Igor Iatsunskyi, Paweł Piotr Michałowski, Karol Załęski, Cassandre Lamboux, Syreina Sayegh, Elissa Makhoul, Andreu Cabot, Xingqi Chang, Mikhael Bechelany, and Emerson Coy. ACS AppliedMaterials & Interfaces Article ASAP, DOI: 10.1021/acsami.3c18935
ChemRxiv	SC Ultra	2024	Dataset for the synthesis and characterization of disordered metallic carbon materials from graphene edge chemistry. Katarzyna Z. Donato, Gavin K. W. Koon, Sarah J. Lee, Alexandra Carvalho, Hui Li Tan, Mariana C. F. Costa, Jakub Tolasz, Petra Ecorchard, Paweł P. Michałowski, Ricardo K. Donato, A. H. Castro Neto. https://chemrxiv.org/engage/chemrxiv/article-details/65e10b469138d231615c3d76
Journal of Low Temperature Physics	SC Ultra	2024	Fabrication and Characterization of Boron-Implanted Silicon Superconducting Thin Films on SOI Substrates for Low-Temperature Detectors. A. Aliane · L. Dussopt · S. Kerdilès · H. Kaya · P. Acosta-Alba · N. Bernier ·A.-M. Papon · E. Martinez · M. Veillerot · F. Lefloch. https://doi.org/10.1007/s10909-024-03122-0
Crystal growth and design	SC Ultra	2024	Monocrystalline GaN Diluted with up to 7% Arsenic Grown by MOVPE. Wojciech Olszewski,* Dominika Majchrzak, Miłosz Grodzicki, Jarosław Serfińczuk, Sandeep Gorantla,Damian Pucicki, Paweł Piotr Michałowski, Robert Kudrawiec, and Detlef Hommel. https://doi.org/10.1021/acs.cgd.3c01486
Advaned Electronic Materials	SC Ultra	2024	Control of Ferroelectricity in Solution-Processed Hafnia Films Through Annealing Atmosphere. Barnik Mandal, Nathalie Valle, Brahime El Adib, Stéphanie Girod, Kevin Menguelti, Yves Fleming, Patrick Grysan, Emmanuel Defay, and Sebastjan Glinsek. Adv. Electron. Mater. 2024, 2300893. https://doi.org/10.1002/aelm.202300893
Nature Materials	SC Ultra	2024	MXenes with ordered triatomic-layer borate polyanion terminations. Dongqi Li, Wenhao Zheng, Sai Manoj Gali, Kamil Sobczak, Michal Horák, Josef Polčá, Nikolaj Lopatik, Zichao Li, Jiaxu Zhang, Davood Sabaghi, Shengqiang Zhou, Paweł P. Michałowski, Ehrenfried Zschech, Eike Brunner, Mikołaj Donten, Tomáš Šikola, Mischa Bonn, Hai I. Wang, David Beljonne, Minghao Yu, Xinliang Feng. https://doi.org/10.1038/s41563-024-01911-2
ChemRxiv	SC Ultra	2024	Alkali cation stabilization of defects in 2D MXenes at ambient and elevated temperatures. Brian C. Wyatt, Matthew G. Boebinger, Zachary D. Hood, Shiba Adhikari, Paweł Piotr Michałowski, Srinivasa Kartik Nemani, Murali Gopal Muraleedharan, Annabelle Bedford, Wyatt J. Highlan, Paul R. C. Kent, Raymond R. Unocic, Babak Anasori. https://doi.org/10.26434/chemrxiv-2024-8tlrd
Nature Scientific Report	SC Ultra	2024	Deep-level defects induced by implantations of Si and Mg ions into undoped epitaxial GaN. Paweł Kamiński, Andrzej Turos, Roman Kozłowski, Kamila Stefańska-Skrobas, Jarosław Żelazko, and Ewa Grzanka. Sci Rep. 2024; 14: 14272. https://www.nature.com/articles/s41598-024-65142-w.
J. Vac. Sci. Technol	SC Ultra	2024	OrbiSIMS depth profiling of semiconductor materials—Useful yield and depth resolution. Yundong Zhou, Alexis Franquet, Valentina Spampinato, Alex Merkulov, Michael R. Keenan, Paul A. W. van der Heide, Gustavo F. Trindade, Wilfried Vandervorst and Ian S. Gilmore. J. Vac. Sci. Technol. A 42, 053208 (2024); doi: 10.1116/6.0003821

Appl. Mater. Interfaces	SC Ultra	2024	Fabrication and Performance Evaluation of a Nanostructured ZnO-Based Solid-State Electrochromic Device. Marivone Gusatti,* Daniel Aragão Ribeiro de Souza, Mario Barozzi, Rossana Dell'Anna, Elena Missale, Lia Vanzetti, Massimo Bersani, and Marcelo Nalin. ACS Appl. Mater. Interfaces. doi: 10.1021/acsami.4c10545
JACS	SC Ultra	2024	Synthesis of Three Isoelemental MXenes and Their Structure–Property Relationships. Marley DownesChristopher E. ShuckRuocun John WangPaweł Piotr MichałowskiJonathan ShochatDanzhen ZhangMikhail ShekhirevYizhou YangNestor J. ZaluzecRaul ArenalSteven J. MayYury Gogotsi. https://doi.org/10.1021/jacs.4c11111
Photonics	SC Ultra	2024	MOCVD Grown InGaAs/InAlAs Quantum Cascade Lasers Emitting at 7.7 µm. Maciej Bugajski, Andrzej Kolek,Grzegorz Hałdaś, Włodzimierz Strupiński, Iwona Pasternak, Walery Kołkowski and Kamil Pierściński. Photonics 2024, 11(12), 1195; https://doi.org/10.3390/photonics11121195
Small Methods	SC Ultra	2024	Secondary Ion Mass Spectrometry Approach for Measuring the Diffusion Range in Optical Fibers with Nanostructured Cores. Paweł P. Michałowski, Dariusz Pysz, Marcin Franczyk, and Ryszard Buczynski. https://doi.org/10.1002/smtd.202401601
Materials Today	SC Ultra	2024	Disordered metallic carbon materials from graphene edge chemistry. Katarzyna Z Donato, Gavin KW Koon, Sarah J Lee, Alexandra Carvalho, Hui Li Tan, Mariana CF Costa, Jakub Tolasz, Petra Ecorchard, Paweł P Michałowski, Ricardo K Donato, AH Castro Neto. Materials Today 79,49–59 (2024).
ECS Transactions	SC Ultra	2024	Advanced SiGe: B Raised Sources and Drains for p-type FD-SOI MOSFETs. Jean-Michel Hartmann, Francois Aussenac, Olivier Glorieux, David Cooper, Sebastien Kerdilès, Zdenek Chalupa, Francois Boulard, Heimanu Niebojewski, Blandine Duriez, Thomas Bordignon, Sebastien Peru, Pawel Michałowski, Richard Daubriac, Fuccio Cristiano. ECS Transactions 114(2),185 (2024).
Solid State Phenomena	SC Ultra	2024	Transient-Enhanced Diffusion of Implanted Aluminum in 4H-SiC. Kristijan Luka Mletschnig, Paweł Piotr Michałowski, Peter Pichler. Solid State Phenomena 359,41–46 (2024).
Nanoscale Horizons	SC Ultra	2024	Unraveling the composition of each atomic layer in the MXene/MAX phase structure–identification of oxycarbide, oxynitride, and oxycarbonitride subfamilies of MXenes. Paweł Piotr Michałowski. Nanoscale Horizons 9,1493–1497 (2024).
Materials Science in Semiconductor Processing	SC Ultra	2024	Thickness and Mg doping of graded AlGaN layers: Influence on contact layer's structural and electrical properties for DUV emitters Dominika Majchrzak, Lan Maria Tran, Michał Babij, Jarosław Serafińczuk, Wojciech Olszewski, Rafał Kuna, Katarzyna Opołczyńska, Adrianna Piejko, Paweł Piotr Michałowski, Robert Kudrawiec, Detlef Hommel. Materials Science in Semiconductor Processing 178,108452 (2024).
Carbon	SC Ultra	2024	Unraveling the role of boron dimers in the electrical anisotropy and superconductivity in boron-doped diamond Michał Sobaszek, Soonho Kwon, Tomasz Klimczuk, Paweł P Michałowski, Jacek Ryl, Bogdan Rutkowski, Dongying Wang, Xinwei Li, Marc Bockrath, Robert Bogdanowicz, William A Goddard III. Carbon 228,119337 (2024).
Materials Science in Semiconductor Processing	SC Ultra	2024	TCAD modeling and simulation of self-limiting oxide growth and boron segregation during vertical silicon nanowire processing Chiara Rossi, Jonas Müller, Peter Pichler, Paweł Piotr Michałowski, Guilhem Larrieu Materials Science in Semiconductor Processing 174,108217 (2024)
European Union's Horizon 2020 research and innovation programme	SC Ultra	2023	Modeling Unconventional Nanoscaled Device FABrication. R. Daubriac, R. Demoulin, J. Muller, F. Cristiano, G. Larrieu, M. Opprecht, S. Kerdiles, J.-M. Hartmann, P. P. Michałowski, A. La Magna, D. Ricciarelli. https://www.mundfab.eu/content/dam/iisb/mundfab/documents/public-deliverables/2023-01-09-mundfab-d46-as-submitted.pdf
Measurement	SC Ultra	2023	Secondary ion mass spectrometry quantification of boron distribution in an array of silicon nanowires. Paweł Piotr Michałowski, Jonas Müller, Chiara Rossi, Alexander Burenkov, Eberhard Bär, Guilhem Larrieu, Peter Pichler. Measurement, Volume 211, 2023, 112630, ISSN 0263-2241. https://doi.org/10.1016/j.measurement.2023.112630.
Opto-Electronics Review	SC Ultra	2023	Multi-technique characterisation of InAs-on-GaAs wafers with circular defect pattern. Jacek Boguski, Jarosław Wróbel, Sebastian Złotnik, Bogusław Budner, Malwina Liszewska, Łukasz Kubiszyn, Paweł P. Michałowski, Łukasz Ciura, Paweł Moszczyński, Sebastian Odrzywolski, Bartłomiej Jankiewicz, Jerzy Wróbel. Opto-Electronics Review 31 (2023) e144564. https://doi.org/10.24425/opelre.2023.144564

Advanced Energy Materials	SC Ultra	2023	Vacuum-Healing of Grain Boundaries in Sodium-Doped CuInSe2 Solar Cell Absorbers. Finn Babbe, Nicoleta Nicoara, Harvey Guthrey, Nathalie Valle, Omar Ramirez Sanchez, Damien Aureau, Hossam Elanzeery, Deepanjan Sharma, José Luís Virtuoso, Jean-Nicolas Audinot, Anastasiya Zelenina, Sevan Gharabeiki, Tom Wirtz, Susanne Siebentritt, Phillip J. Dale, Sascha Sadewasser, and Diego Colombara. Adv. Energy Mater. 2023, 2204183. DOI: 10.1002/aenm.202204183.
Scientific Report Nature	SC Ultra	2023	Insights into the physical and chemical properties of struvite crystal surfaces in terms of the efectiveness of bacterial adhesion. Jolanta Prywer, AgnieszkaTorzewska, Michał Cichomski & Paweł Piotr Michałowski. Scientifc Reports, (2023) 13:5557, https://doi.org/10.1038/s41598-023-32758-3
Journal of Vacuum Science & Technology B	SC Ultra	2023	Characterization of GaN structures for power electronics by secondary ion mass spectrometry and atomic force microscope approach. Tarek Spelta; Marc Veillerot; Eugénie Martinez; Nicolas Chevalier; Denis Mariolle; Roselyne Templier; Bassem Salem; Pedro Fernandes Paes Pinto Rocha; Laura Vauche; Sarah Boubenia; Bérangère Hyot. https://pubs.aip.org/avs/jvb/article/41/3/034003/2884488
Materials Science in Semiconductor Processing	SC Ultra	2023	Nanosecond laser annealing of pseudomorphic GeSn layers: Impact of Sn content. M. Frauenrath, P. Acosta Alba, O. Concepción, J.-H. Bae, N. Gauthier, E. Nolot, M. Veillerot, N. Bernier, D. Buca, J.-M. Hartmann. Materials Science in Semiconductor Processing, Volume 163, 2023, 107549, ISSN 1369-8001. https://doi.org/10.1016/j.mssp.2023.107549.
Thin Solid Films	SC Ultra	2023	Driving up the quality of Metal Organic Chemical Vapor Deposition grown epitaxial wafers for highly innovative photonic applications. I. Pasternak, W. Kolkowski, J. Jureńczyk , K. Matuszelański and W. Strupinski. Thin Solid Films (2023), https://doi.org/10.1016/j.tsf.2023.139906
Papers SSRN	SC Ultra	2023	Investigations of the growth mechanisms of anatase TiO2 thin films deposited by pulsed Electron Cyclotron Wave Resonance plasma at low substrate temperature. DEY Benjamin, BULOU Simon, VALLE Nathalie, RICHARD-PLOUET Mireille, GRANIER Agnès, CHOQUET Patrick. Paprers SSRN. https://dx.doi.org/10.2139/ssrn.4412897.
Journal of Alloys and Coumpounds	SC Ultra	2023	Influence of Si addition on the phase structure and oxidation behavior of PVD AlTiN and AlTiCrN coatings using high-resolution characterization techniques. M-R. Alhafian, N. Valle, J-B. Chemin, L. Bourgeois, M. Penoy, R. Useldinger, J. Ghanbaja, F. Mücklich, P. Choquet. Journal of Alloys and Compounds, Volume 968, 2023, 171800, ISSN 0925-8388, https://doi.org/10.1016/j.jallcom.2023.171800.
Arxiv	SC Ultra	2023	Ultrafast optical properties of stoichiometric and non stoichiometric refractory metal nitrides TiNx, ZrNx, and HfNx. Jarosław Judek, Rakesh Dhama, Alessandro Pianelli, Piotr Wróbel, Paweł Piotr Michałowski, Jayanta Dana and Humeyra Caglayan. https://arxiv.org/ftp/arxiv/papers/2309/2309.05593.pdf
Crystals	SC Ultra	2023	Development of a Real-Time Boron Concentration Monitoring Technique for Plasma Doping Implantation. Su-Young Chai and Sung-Hoon Choa. Crystals 2023, 13, 1665. https://doi.org/10.3390/cryst13121665.
Applied Surface Science	SC Ultra	2023	From DFT investigations of oxygen-implanted molybdenum disulfide to temperature-induced stabilization of MoS2/MoO3. Sylwia Kozdra, Adrianna Wójcik, Tamal Das, Paweł Piotr Michałowski Applied Surface Science 631, 157547 (2023) https://urldefense.com/v3/__https://www.sciencedirect.com/science/article/pii/S0169433223012254__;!!HKOSU0g EZuoCOjRhuyKGXvOOLZeSLF5cidEvvPjUJA2epWyvm9Ac8LF-TkiiXsLFaFypAFrEImWyRemeMsGhWnImZJiq1JEz3kMnWqBBmBTVKeofjyWOX6T$
Materials Science in Semiconductor Processing	SC Ultra	2023	Impact of surface reflectivity on the ultra-fast laser melting of silicon-germanium alloys. Damiano Ricciarelli, Giovanni Mannino, Ioannis Deretzis, Gaetano Calogero, Giuseppe Fisicaro, Richard Daubriac, Fuccio Cristiano, Remi Demoulin, Paweł Piotr Michałowski, Pablo Acosta-Alba, Jean-Michel Hartmann, Sébastien Kerdilès, Antonino La Magna Materials Science in Semiconductor Processing 165, 107635 (2023) https://urldefense.com/v3/__https://www.sciencedirect.com/science/article/pii/S1369800123003281__;!!HKOSU0g!EZuoCOjRhuyKGXvOOLZeSLF5cidEvvPjUJA2epWyvm9Ac8LF-TkiiXsLFaFypAFrEImWyRemeMsGhWnImZJiq1JEz3kMnWqBBmBTVKeofhhHaL8q$
Semiconductor Science and Technology	IMS Wf	2023	Estimation of the melting threshold for Ti supersaturated Si using Time Resolved Reflectometry and Haze Measurements. Daniel Montero, D. Caudevilla, Sari Algaidy, Rodrigo García-Hernansanz, Andrej Suler, Pablo Acosta-Alba, Sebastien Kerdiles, David Pastor, Eric Garcia-Hemme, François Roy and Javier Olea. DOI 10.1088/1361-6641/acb16d.
JVSTB	IMS Wf	2023	Determining the oxygen detection limit with magnetic sector dynamic secondary ion mass spectrometry (SIMS). A; Merkulov.Journal of Vacuum Science & Technology B 41, 044009 (2023). https://doi.org/10.1116/6.0002578

IFPA	IMS Wf	2023	Case Study of SIMS Analysis on Insulators. Yun Wang, Kian Kok Ong, Han Wei Teo, Ley Hong Khoo, Ramesh Rao Nistala, Zhi Qiang Mo, Soh Ping Neo. 2023 IEEE International Symposium on the Physical and Failure Analysis of Integrated Circuits (IPFA), Pulau Pinang, Malaysia, 2023, pp. 1-4, doi: 10.1109/IPFA58228.2023.10249031.
ECS Journal of Solid State Science and Technology	IMS Wf	2022	Post-metallization annealing and photolithography effects in p-type Ge/Al2O3/Al MOS structures. V. Ioannou-Sougleridis, S. Alafakis, B. Pécz, D. Velessiotis, N. Z. Vouroutzis, S. Ladas, M. Barozzi, G. Pepponi and D. Skarlatos. (2022). ECS J. Solid State Sci. Technol. 11 045006. https://doi.org/10.1149/2162-8777/ac62f2
ECS Journal of Solid State Science and Technology	SC Ultra	2022	Post-metallization annealing and photolithography effects in p-type Ge/Al2O3/Al MOS structures. V. Ioannou-Sougleridis, S. Alafakis, B. Pécz, D. Velessiotis, N. Z. Vouroutzis, S. Ladas, M. Barozzi, G. Pepponi and D. Skarlatos. (2022). ECS J. Solid State Sci. Technol. 11 045006. https://doi.org/10.1149/2162-8777/ac62f2
Condensed Matter	SC Ultra	2022	Post-deposition annealing and interfacial ALD buffer layers of Sb2Se3/CdS stacks for reduced interface recombination and increased open-circuit voltages. Thomas Paul Weiss, Ignacio Minguez-Bacho, Elena Zuccalà, Michele Melchiorre, Nathalie Valle, Brahime El Adib, Tadahiro Yokosawa, Erdmann Spiecker, Julien Bachmann, Phillip J. Dale, Susanne Siebentritt. (2022). https://doi.org/10.48550/arXiv.2204.13138
Journal of Vacuum Science & Technology A	SC Ultra	2022	On the interplay between a novel iron and iron-carbide atomic layer deposition process, the carbon nanotube growth, and the metal–carbon nanotube coating properties on silica substrates. Tairan da Cunha, Noureddine Adjeroud, Jérôme Guillot, Benoit Duez, Damien Lenoble, and Didier Arl. (2022). Journal of Vacuum Science & Technology A 40, 033415 (2022); https://doi.org/10.1116/6.0001806
Chemistry of materials	SC Ultra	2022	Diazonium-Based Covalent Molecular Wiring of Single-Layer Graphene Leads to Enhanced Unidirectional Photocurrent Generation through the p-doping Effect. Margot Jacquet, Silvio Osella, Ersan Harputlu, Barbara Pałys, Monika Kaczmarek, Ewa K. Nawrocka, Adam A. Rajkiewicz, Marcin Kalek, Paweł P. Michałowski, Bartosz Trzaskowski, C. Gokhan Unlu, Wojciech Lisowski, Marcin Pisarek, Krzysztof Kazimierczuk, Kasim Ocakoglu, Agnieszka Więckowska, and Joanna Kargul*. (2022). Chem. Mater. 2022, 34, 3744−3758. https://doi.org/10.1021/acs.chemmater.2c00088
Applied surface science	SC Ultra	2022	Thermal oxidation of [0001] GaN in water vapor compared with dry and wet oxidation: Oxide properties and impact on GaN. Łukasz Janicki, Ryszard Korbutowicz, Mariusz Rudzi´nski, Paweł Piotr Michałowski, Sebastian Złotnik, Miłosz Grodzicki, Sandeep Gorantla, Jarosław Serafi´nczuk, Detlef Hommel, Robert Kudrawiec. (2022). Volume 598, 1 October 2022, 153872. https://doi.org/10.1016/j.apsusc.2022.153872.
2D Materials	SC Ultra	2022	Three-step, transfer-free growth of MoS2/WS2/graphene vertical van der Waals heterostructure. Jakub Sitek, Iwona Pasternak, Karolina Czerniak-Łosiewicz, Michał ´Swiniarski Paweł P Michałowski, Clifford McAleese, Xiaochen Wang, Ben R Conran, Konrad Wilczy´nski, Michał Macha, Aleksandra Radenovi, Mariusz Zdrojek and Włodek Strupi´nski. (2022). 2D Mater. 9 (2022) 025030. https://doi.org/10.1088/2053-1583/ac5f6d.
Materials	SC Ultra	2022	Development of Quaternary InAlGaN Barrier Layer for HighElectron Mobility Transistor Structures. Justinas Jorudas , Paweł Prystawko, Art ¯ ur Šimukovi ˇ, Ram ¯ unas Aleksiej ¯ unas, J ¯ uras Mickevi ˇcius,Marcin Kry´sko, Paweł Piotr Michałowski and Irmantas Kašalynas. (2022). Materials 2022, 15, 1118. https://doi.org/10.3390/ma15031118
Journal of Materials Science	SC Ultra	2022	Insights on boron impact on structural characteristics in epitaxially grown BGaN. Ewelina B. Mo_zd_zyn´ska , Sebastian Złotnik, Paweł Ciepielewski, Jarosław Gaca, Marek Wo´ jcik, Paweł P. Michałowski, Krzysztof Rosin´ ski, Karolina Pie¸tak1, Mariusz Rudzin´ ski, El_ zbieta Jezierska, and Jacek M. Baranowski. (2022). J Mater Sci (2022) 57:7265–7275. https://doi.org/10.1007/s10853-022-07085-z.
IEEE Journal of Photovoltaics	SC Ultra	2022	Bulk Defects and Hydrogenation Kinetics in Crystalline Silicon Solar Cells With Fired Passivating Contacts. Mario Lehmann; Anatole Desthieux; Nathalie Valle; Audrey Morisset; Philippe Wyss; Santhana Eswara; Tom Wirtz; Andrea Ingenito, Pere Roca i Cabarrocas, Christophe Ballif, Franz-Josef Haug. (2022). IEEE Journal of Photovoltaics, vol. 12, no. 3, pp. 711-721, May 2022. doi: 10.1109/JPHOTOV.2022.3161871.
Applied Physics	SC Ultra	2022	Solar cell efficiency, diode factor and interface recombination: insights from photoluminescence. Taowen Wang, Florian Ehre, Thomas Paul Weiss, Boris Veith-Wolf, Valeriya Titova, Nathalie Valle, Michele Melchiorre, Jan Schmidt, and Susanne Siebentritt. arXiv:2204.06483. https://doi.org/10.48550/arXiv.2204.06483

Physical Review B	SC Ultra	2022	Magnetic damping in ferromagnetic/heavy-metal systems: The role of interfaces and the relation to proximity-induced magnetism. C. Swindells, H. Głowiński, Y. Choi, D. Haskel, P. P. Michałowski, T. Hase, F. Stobiecki, P. Kuświk, and D. Atkinson. Phys. Rev. B 105, 094433. https://doi.org/10.1103/PhysRevB.105.094433.
PhD Thesis	SC Ultra	2022	Characterization and Development of Fired Passivating Contacts for Silicon Solar Cells. Mario Joe LEHMANN. PhD thesis
Corrosion Science	SC Ultra	2022	Study of the oxidation mechanism at high temperature of nanofiber textured AlTiCrN coatings produced by physical vapor deposition using high-resolution characterization techniques. M-R.Alhafian , J-B.Chemin, N.Valle, El Adib, M.Penoy, L.Bourgeois, J.Ghanbaja, J.Barrirero, F.Soldera, F.Mücklich, P.Choquet. Volume 201, June 2022, 110226. https://doi.org/10.1016/j.corsci.2022.110226
Physica E: Low-dimensional Systems and Nanostructures	SC Ultra	2022	Contamination-induced inhomogeneity of noise sources distribution in Al2O3-passivated quasi-free-standing graphene on 4H-SiC(0001). T. Ciuk, Ł. Ciura, P.P. Michałowski, J. Jagiełło, A. Dobrowolski, K. Piętak, D. Kalita, M. Wzorek, R. Budzich, D. Czołak, A. Kolek. Volume 142, August 2022, 115264. https://doi.org/10.1016/j.physe.2022.115264
Scripta Materialia	SC Ultra	2022	Empirical indication for desalinating properties of porous boron nitride, Adrianna Wójcik, Aleksandra K. Dąbrowska, Sylwia Kozdra, Johannes Binder, Włodzimierz Strupiński, Roman Stępniewski, Andrzej Wysmołek, Tomasz Strachowski,Marek Wzorek, Agnieszka Malinowska, Edyta Wierzbicka, Ryszard Diduszko, Paweł P. Michałowski. Volume 220, 2022, 114943. https://doi.org/10.1016/j.scriptamat.2022.114943.
Materials Science and Engineering: B	SC Ultra	2022	Photoelectric, optical and microstructural characterization of thin palladium silicide (Pd2Si) layers fabricated by magnetron sputtering from a stoichiometric target. K. Piskorski, M. Wzorek, M. Ekielski, L. Dobrzański, J. Gaca, A. Malinowska, P. Michałowski, M.A. Borysiewicz,.Volume 283, 2022, 115831. https://doi.org/10.1016/j.mseb.2022.115831.
Analytical Chemistry	SC Ultra	2022	Magnetic Sector Secondary Ion Mass Spectrometry on FIB-SEM Instruments for Nanoscale Chemical Imaging. Olivier De Castro, Jean-Nicolas Audinot, Hung Quang Hoang, Chérif Coulbary, Olivier Bouton, Rachid Barrahma, Alexander Ost, Charlotte Stoffels, Chengge Jiao, Mikhail Dutka, Michal Geryk, and Tom Wirtz. Anal. Chem. 2022, 94, 30, 10754–10763 https://doi.org/10.1021/acs.analchem.2c01410
J. Phys. Energy	SC Ultra	2022	Quantitative evaluation of biaxial compressive strain and its impact on proton conduction and diffusion in yttrium-doped barium zirconate epitaxial thin films. Junji Hyodo and Yoshihiro Yamazaki. J. Phys. Energy. https://doi.org/10.1088/2515-7655/ac889e
ECS Transactions	SC Ultra	2022	Low Temperature Epitaxy of In Situ GaDoped Si1-XGex: Dopant Incorporation, Structural and Electrical Properties. Gianluca Rengo, Clement Porret, Andriy Yakovitch Hikavyy, Gitte Coenen, Mustafa Ayyad, Richard J. H. Morris, Simone Pollastri, Danilo Oliveira De Souza, Didier Grandjean, Roger Loo and Andre Vantomme. ECS Transactions, Volume 109, Number 4. https://doi.org/10.1149/10904.0249ecst
Progress in Photovoltaics	SC Ultra	2022	Post-deposition annealing and interfacial atomic layer deposition buffer layers of Sb2Se3/CdS stacks for reduced interface recombination and increased open-circuit voltages. Thomas Paul Weiss, Ignacio Minguez-Bacho, Elena Zuccalà, Michele Melchiorre, Nathalie Valle, Brahime El Adib, Tadahiro Yokosawa, Erdmann Spiecker, Julien Bachmann, Phillip J. Dale1, Susanne Siebentritt. Prog Photovolt Res Appl. 2022;1–17. https://doi.org/10.1002/pip.3625
Progress in Photovoltaics	SC Ultra	2022	Wafer-scale Ge epitaxial foils grown at high growth rates and released from porous substrates for triple-junction solar cells. Valérie Depauw,Clément Porret,Myriam Moelants,Emma Vecchio,Koen Kennes,Han Han,Roger Loo,Jinyoun Cho,Guillaume Courtois,Rufi Kurstjens,Kristof Dessein,Víctor Orejuela,Clara Sanchez-Perez,Ignacio Rey-Stolle,Iván García. https://doi.org/10.1002/pip.3634
Nature Nanotechnology	SC Ultra	2022	Oxycarbide MXenes and MAX phases identification using monoatomic layer-by-layer analysis with ultralow-energy secondary-ion mass spectrometry. Paweł Piotr Michałowski, Mark Anayee, Tyler S Mathis, Sylwia Kozdra, Adrianna Wójcik, Kanit Hantanasirisakul, Iwona Jóźwik, Anna Piątkowska, Małgorzata Możdżonek, Agnieszka Malinowska, Ryszard Diduszko, Edyta Wierzbicka, Yury Gogotsi Nature Nanotechnology 17, 1192-1197 (2022)
Polymer	SC Ultra	2022	Poly (vinylidene fluoride) solid polymer electrolyte structure revealed by secondary ion mass spectrometry. Sylwia Kozdra, Adrianna Wójcik, Małogrzata Możdżonek, Łukasz Florczak, Ireneusz Opaliński, Paweł Piotr Michałowski Polymer 259, 125364 (2022)

Measurement	SC Ultra	2022	Precise localization of contaminants in graphene with secondary ion mass spectrometry. Paweł Piotr Michałowski, Sylwia Kozdra, Iwona Pasternak, Jakub Sitek, Adrianna Wójcik, Włodek Strupiński. Measurement 187, 110308 (2022)
Materials	SC Ultra	2022	Mechanisms of Ohmic Contact Formation of Ti/Al-Based Metal Stacks on p-Doped 4H-SiC. Matthias Kocher, Mathias Rommel, Paweł Piotr Michałowski, Tobias Erlbacher Materials 15, 50 (2022).
Polyhedron	SC Ultra	2022	Insight into structure-property relationship of organometallic terpyridine wires: Combined theoretical and experimental study. Sylwia Kozdra, Margot Jacquet, Joanna Kargul, Karol Hęclik, Adrianna Wójcik, Paweł Piotr Michałowski. Polyhedron 213, 115628 (2022)
Materials	SC Ultra	2021	Titanium Nitride as a Plasmonic Material from Near-Ultraviolet to Very-Long-Wavelength Infrared Range. Jarosław Judek, Piotr Wróbel, Paweł Piotr Michałowski, Monika Ożga, Bartłomiej Witkowski, Aleksandra Seweryn, Michał Struzik, Cezariusz Jastrzębski, Krzysztof Zberecki. Materials 14, 7095 (2021)
Applied Physics Letters	SC Ultra	2021	Proximity-induced magnetism and the enhancement of damping in ferromagnetic/heavy metal systems. C. Swindells, H. Głowiński, Y. Choi, D. Haskel, P.P. Michałowski, T. Hase, P. Kuświk, D. Atkinson. Applied Physics Letters 119, 152401 (2021)
Nanoscale	SC Ultra	2021	Development of a universal conductive platform for anchoring photo- and electroactive proteins using organometallic terpyridine molecular wires. Margot Jacquet, Miriam Izzo, Silvio Osella, Sylwia Kozdra, Paweł P. Michałowski, Dariusz Gołowicz, Krzysztof Kazimierczuk, Maciej T. Gorzkowski, Adam Lewera, Marian Teodorczyk, Bartosz Trzaskowski, Rafał Jurczakowski, Daniel T. Gryko, Joanna Kargul. Nanoscale 13, 9773 (2021)
Measurement	SC Ultra	2021	Defect-mediated sputtering process of boron nitride during high incident angle low-energy ion bombardment. Paweł Piotr Michałowski, Dawid Maciążek, Zbigniew Postawa, Piotr A Caban, Sylwia Kozdra, Adrianna Wójcik, Jacek M Baranowski. Measurement 179, 109487 (2021)
Current Applied Physics	SC Ultra	2021	Highly-doped p-type few-layer graphene on UID off-axis homoepitaxial 4H-SiC. Tymoteusz Ciuk, Wawrzyniec Kaszub, Kinga Kosciewicz, Artur Dobrowolski, Jakub Jagiello, Adrianna Chamryga, Jaroslaw Gaca, Marek Wojcik, Dariusz Czolak, Beata Stanczyk, Krystyna Przyborowska, Roman Kozlowski, Michal Kozubal, Pawel Piotr Michalowski, Maciej Jan Szary, Pawel Kaminski. Current Applied Physics 27, 17-24 (2021)
Journal of Materials Chemistry	SC Ultra	2021	Effect of oxidation temperature on the inhomogeneity of chemical composition and density in nanometric SiO2 films grown on 4H-SiC. Paweł Kamiński, Rafał Budzich, Jarosław Gaca, Paweł Piotr Michałowski, Roman Kozłowski, Anna Harmasz, Tymoteusz Ciuk, Janusz Płocharski. Journal of Materials Chemistry C 9, 4393-4404 (2021)
Advanced Optical Materials	SC Ultra	2021	Arsenic-Induced Growth of Dodecagonal GaN Microrods with Stable a-Plane Walls. Paulina Ciechanowicz, Sandeep Gorantla, Paweł Piotr Michałowski, Ewelina Zdanowicz, Jean-Guy Rousset, Daria Hlushchenko, Krzysztof Adamczyk, Dominika Majchrzak, Robert Kudrawiec, Detlef Hommel. Advanced Optical Materials 9, 2001348 (2021)
Materials Science in Semiconductor Processing	SC Ultra	2021	Selective etching of p-GaN over Al0.25Ga0.75N in Cl2/Ar/O2 ICP plasma for fabrication of normally-off GaN HEMTs. Andrzej Taube, Maciej Kamiński, Marek Ekielski, Renata Kruszka, Joanna Jankowska-Śliwińska, Paweł Piotr Michałowski, Joanna Zdunek, Anna Szerling. Materials Science in Semiconductor Processing 122, 105450 (2021)
Journal of Analytical Atomic Spectrometry	SC Ultra	2021	Electrically active and hydrogen passivated Zn in GaAs/AlGaAs specifically distinguished during secondary ion mass spectrometry depth profiling. Adrianna Wójcik, Walery Kolkowski, Iwona Pasternak, Włodzimierz Strupiński, Sylwia Kozdra, Paweł Piotr Michałowski. Journal of Analytical Atomic Spectrometry 36, 178–184 (2021)
Journal of Applied Physics	SC Ultra	2020	Two-dimensional electron gas at the AlGaN/GaN interface: Layer thickness dependence. Vladimir N. Popok, Piotr A. Caban, Pawel Piotr Michalowski, Ryan Thorpe, Leonard C. Feldman, and Kjeld Pedersen. Journal of Applied Physics 127, 115703 (2020)
Journal of Alloys and Compounds	SC Ultra	2020	Carbon incorporation in boron nitride grown by MOCVD under N2 flow. P.A. Caban, P.P. Michalowski, I. Wlasny, J. Gaca, M. Wojcik, P. Ciepielewski, D. Teklinska, J.M. Baranowski. Journal of Alloys and Compounds, Volume 815, 152364 (2020)

Journal of Physics: Photonics 2	SC Ultra	2020	Next generation low temperature polycrystalline materials for above IC electronics. High mobility n- and p-type III–V metalorganic vapour phase epitaxy thin films on amorphous substrates. Agnieszka Gocalinska, Andrea Pescaglini, Eleonora Secco, Enrica E Mura, Kevin Thomas, Anya Curran, Farzan Gity, Roger Nagle, Michael Schmidt, Paweł Piotr Michałowski, Paul K Hurley, Ian Povey, Emanuele Pelucchi. Journal of Physics: Photonics 2, 025003 (2020)
Journal of Visualized Experiments	SC Ultra	2020	3D Depth Profile Reconstruction of Segregated Impurities using Secondary Ion Mass Spectrometry. Paweł Piotr Michałowski, Sebastian Zlotnik, Iwona Jóźwik, Adrianna Chamryga, Mariusz Rudziński. Journal of Visualized Experiments 158, e61065 (2020)
ournal of Analytical Atomic Spectrometry	SC Ultra	2020	Titanium pre-sputtering for an enhanced secondary ion mass spectrometry analysis of atmospheric gas elements. Paweł Piotr Michałowski. Journal of Analytical Atomic Spectrometry 35, 1047 (2020)
Journal of Materials Science: Materials in Electronics	SC Ultra	2020	Phosphorus implantation of Mg-doped (Al)GaN heterostructures: structural examination and depth profiling. Karolina Piętak, Sebastian Złotnik, Ewelina Rozbiegała, Paweł Piotr Michałowski, Marek Wójcik, Jarosław Gaca, Mariusz Rudziński. Journal of Materials Science: Materials in Electronics 31, 17892–17902 (2020)
Physica Status Solidi - Rapid Research Letters	SC Ultra	2020	Locally-Strain-Induced Heavy-Hole-Band Splitting Observed in Mobility Spectrum of p-Type InAs Grown on GaAs. Jarosław Wróbel, Gilberto A. Umana-Membreno, Jacek Boguski, Dariusz Sztenkiel, Paweł Piotr Michałowski, Piotr Martyniuk, Lorenzo Faraone, Jerzy Wróbel, Antoni Rogalski. Physica Status Solidi - Rapid Research Letters 14, 1900604 (2020
Journal of Applied Physics	SC Ultra	2020	Two-dimensional electron gas at the AlGaN/GaN interface: Layer thickness dependence. Vladimir N. Popok, Piotr Caban, Paweł Piotr Michałowski, Ryan Thorpe, Leonard C. Feldman, Kjeld Pedersen. Journal of Applied Physics 127, 115703 (2020)
IEEE Journal of Photovoltaics	SC Ultra	2020	Influence of Silicon Layers on the Growth of ITO and AZO in Silicon Heterojunction Solar Cells. Alexandros Cruz, Florian Ruske, Alberto Eljarrat, Paweł Piotr Michałowski, Anna B. Morales-Vilches, Sebastian Neubert, Er-Chien Wang, Christoph T. Koch, Bernd Szyszka, Rutger Schlatmann, Bernd Stannowski. IEEE Journal of Photovoltaics 10, 8944078, 703-709 (2020)
Journal of Alloys and Compounds	SC Ultra	2020	Carbon incorporation in boron nitride grown by MOCVD under N2 flow. Piotr Caban, Paweł Piotr Michałowski, Igor Własny, Jarosław Gaca, Marek Wójcik, Paweł Ciepielewski, Dominika Teklińska, Jacek Baranowski. Journal of Alloys and Compounds 815, 152364 (2020)
Physical Review Letters	SC Ultra	2020	Magnetic Domains without Domain Walls: A Unique Effect of He+ Ion Bombardment in Ferrimagnetic Tb/Co Films. Łukasz Frąckowiak, Piotr Kuświk, Gabriel David Chaves-O'Flynn, Maciej Urbaniak, Michał Matczak, Paweł Piotr Michałowski, Andrzej Maziewski, Meike Reginka, Arno Ehresmann, Feliks Stobiecki. Physical Review Letters 124, 047203 (2020)
Journal of Analytical Atomic Spectrometry	SC Ultra	2019	Probing a chemical state during ultra low impact energy secondary ion mass spectrometry depth profiling. Paweł Piotr Michałowski. Journal of Analytical Atomic Spectrometry 34, 1954-1956 (2019)
Applied Surface Science	SC Ultra	2019	Growth and thermal annealing for acceptor activation of p-type (Al)GaN epitaxial structures: Technological challenges and risks. Sebastian Złotnik, Jakub Sitek, Krzysztof Rosiński, Paweł Piotr Michałowski, Jarosław Gaca, Marek Wójcik, Mariusz Rudziński. Applied Surface Science 488, 688-695 (2019)
Journal of Analytical Atomic Spectrometry	SC Ultra	2019	Indium concentration fluctuations in InGaN/GaN quantum wells. Paweł Piotr Michałowski, Ewa Grzanka, Szymon Grzanka, Artur Lachowski, Grzegorz Staszczak, Mike Leszczyński, Andrzej Turos. Journal of Analytical Atomic Spectrometry 34, 1718-1723 (2019)
Chemical Communications	SC Ultra	2019	Three dimensional localization of unintentional oxygen impurities in gallium nitride. Paweł Piotr Michałowski, Sebastian Złotnik, Mariusz Rudziński. Chemical Communications 55, 11539-11542 (2019)
ACS Omega	SC Ultra	2019	Thermal Conversion of Ethanol into Carbon Nanotube Coatings with Adjusted Packing Density. H. Jagalur Basheer, K. Baba, and N. Bahlawane. ACS Omega (2019), 4, 6, 10405–10410
Physical Chemistry Chemical Physics	SC Ultra	2019	Growth of highly oriented MoS2 via an intercalation process in the graphene/SiC(0001) system. Paweł Piotr Michałowski, Piotr Knyps, Paweł Ciepielewski, Piotr Caban, Ewa Dumiszewska, Grzegorz Kowalski, Mateusz Tokarczyk, Jacek Baranowski. Physical Chemistry Chemical Physics 21, 20641-20646 (2019)
Journal of Analytical Atomic Spectrometry	SC Ultra	2019	Secondary ion mass spectrometry investigation of carbon grain formation in boron nitride epitaxial layers with atomic depth resolution. Paweł Piotr Michałowski, Piotr Caban and Jacek Baranowski. Journal of Analytical Atomic Spectrometry 34, 848-853 (2019)
Physical Chemistry Chemical Physics	SC Ultra	2019	Destructive role of oxygen in growth of molybdenum disulfide determined by secondary ion mass spectrometry. Paweł Piotr Michałowski, Piotr Knyps, Paweł Ciepielewski, Piotr Caban, Ewa Dumiszewska and Jacek Baranowski. Physical Chemistry Chemical Physics 21, 8837-8842 (2019)

Materials	SC Ultra	2019	Crystallisation Phenomena of In2O3:H Films. Ruslan Muydinov, Alexander Steigert, Markus Wollgarten, Paweł Piotr Michałowski, Ulrike Bloeck, Andreas Pflug, Darja Erfurt, Reiner Klenk, Stefan Körner, Iver Lauermann and Bernd Szyszka. Materials 12, 266 (2019)
Nature Energy	SC Ultra	2018	A passivating contact for silicon solar cells formed during a single firing thermal annealing. Andrea Ingenito, Gizem Nogay, Quentin Jeangros, Esteban Rucavado, Christophe Allebé, Santhana Eswara, Nathalie Valle, Tom Wirtz, Jörg Horzel, Takashi Koida, Monica Morales-Masis, Matthieu Despeisse, Franz-Josef Haug, Philipp Löper & Christophe Ballif. Nature Energy, volume 3, pages800–808 (2018)
ACS Applied Matererials & Interfaces	SC Ultra	2018	A-Crater-within-a-Crater Approach for Secondary Ion Mass Spectrometry Evaluation of the Quality of Interfaces of Multilayer Devices. Paweł Piotr Michałowski , Wawrzyniec Kaszub, Piotr Knyps, Krzysztof Rosiński, Beata Stańczyk, Krystyna Przyborowska and Ewa Dumiszewska. ACS Applied Matererials & Interfaces 10, 37694-37698 (2018)
Nanotechnology	SC Ultra	2018	Oxygen out-diffusion and compositional changes in zinc oxide during ytterbium ions bombardment. Paweł Piotr Michałowski Jarosław Gaca Marek Wójcik Andrzej Turos. Nanotechnology 29, 425710 (2018)
Carbon	SC Ultra	2018	Thermally activated double-carrier transport in epitaxial graphene on vanadium-compensated 6H-SiC as revealed by Hall effect measurements. Tymoteusz Ciuk, Andrzej Kozlowski, Paweł Piotr Michałowski, Wawrzyniec Kaszub, Michal Kozubal, Zbigniew Rekuc, Jaroslaw Podgorski, Beata Stanczyk, Krystyna Przyborowska, Iwona Jozwik, Andrzej Kowalik, Pawel Kaminski. Carbon 139, 776-781 (2018)
Journal of Crystal Growth	SC Ultra	2018	The role of hydrogen in carbon incorporation and surface roughness of MOCVD-grown thin boron nitride. Piotr A. Caban, Dominika Teklinska, Paweł P. Michałowski, Jaroslaw Gaca, Marek Wojcik, Justyna Grzonka, Pawel Ciepielewski, Malgorzata Mozdzonek, Jacek M. Baranowski. Journal of Crystal Growth 498, 71-76 (2018)
Physical Chemistry Chemical Physics	SC Ultra	2018	Oxygen-induced high diffusion rate of magnesium dopants in GaN/AlGaN based UV LED heterostructures. Paweł Piotr Michałowski, Sebastian Złotnik, Jakub Sitek, Krzysztof Rosińskia and Mariusz Rudzińskia. Physical Chemistry Chemical Physics 20, 13890-13895 (2018)
Nanoscale	SC Ultra	2018	Self-organized multi-layered graphene–boron-doped diamond hybrid nanowalls for high-performance electron emission devices. Kamatchi Jothiramalingam Sankaran, Mateusz Ficek, Srinivasu Kunuku, Kalpataru Panda, Chien-Jui Yeh, Jeong Young Park, Miroslaw Sawczak, Paweł Piotr Michałowski, Keh-Chyang Leou, Robert Bogdanowicz, I-Nan Lin and Ken Haenen. Nanoscale 10, 1345-1355 (2018)
Nanotechnology	SC Ultra	2018	Formation of a highly doped ultra-thin amorphous carbon layer by ion bombardment of Graphene. Paweł Piotr Michałowski, Iwona Pasternak, Paweł Ciepielewski, Francisco Guinea and Włodek Strupiński. Nanotechnology 29, 305302 (2018)
Nanotechnology	SC Ultra	2018	Contamination-free Ge-based graphene as revealed by graphene enhanced secondary ion mass spectrometry (GESIMS). Paweł Piotr Michałowski, Iwona Pasternak and Włodek Strupiński. Nanotechnology 29, 015702 (2018)
Nature Communications	SC Ultra	2018	Sodium enhances indium-gallium interdiffusion in copper indium gallium diselenide photovoltaic absorbers. D. Colombara, F. Werner, T. Schwarz, I. Cañero Infante, Y. Fleming, N. Valle, C. Spindler, E. Vacchieri, G. Rey, M. Guennou, M. Bouttemy, A. Garzón Manjón, I. Peral Alonso, M. Melchiorre, B. El Adib, B. Gault, D. Raabe, Phillip J. Dale & S. Siebentritt. Nature Communications volume 9, Article number: 826 (2018)
Applied Surface Science	SC Ultra	2018	Influence of hydrogen intercalation on graphene/Ge(0 0 1)/Si(0 0 1) interface. Justyna Grzonka, Iw ona Pasternak, Paweł Piotr Michałowski, Valery Kolkovsky and Włodek Strupiński. Applied Surface Science 447, 582-586 (2018)
Nanoscale	SC Ultra	2017	Characterization of the superlattice region of a quantum cascade laser by secondary ion mass spectrometry. Paweł Piotr Michałowski, Piotr Gutowski, Dorota Pierścińska, Kamil Pierściński, Maciej Bugajski and Włodek Strupińskiac. Nanoscale 9, 17571-17575 (2017)
Scientific Reports	SC Ultra	2017	Graphene Enhanced Secondary Ion Mass Spectrometry (GESIMS). Paweł Piotr Michałowski, Wawrzyniec Kaszub, Iwona Pasternak and Włodek Strupiński. Scientific Reports 7, 7479 (2017)
IEEE	SC Ultra	2017	Reproducibility of implanted dosage measurement with CAMECA Wf. Kian Kok Ong, Yun Wang and Zhiqiang Mo. IEEE 24th International Symposium on the Physical and Failure Analysis of Integrated Circuits (2017)
IEEE	SC Ultra	2017	Investigation of Cs+ bombardment effects in ultra-thin oxynitride gate dielectrics characterization by DSIMS. Yun Wang, Kian Kok Ong, Zhi Qiang Mo, Han Wei Teo, Si Ping Zhao. IEEE 24th International Symposium on the Physical and Failure Analysis of Integrated Circuits (2017)

Advanced Materials	SC Ultra	2016	Facet-Independent Electric-Field-Induced Volume Metallization of Tungsten Trioxide Films. S. G. Altendorf, J. Jeong, D. Passarello, N. B. Aetukuri, M. G. Samant, Stuart S. P. Parkin. Advanced Materials, Volume28, Issue26, July 13, (2016), Pages 5284-5292
Appl. Phys. Lett	SC Ultra	2016	Secondary ion mass spectroscopy depth profiling of hydrogen-intercalated graphene on SiC. Pawel Piotr Michalowski, Wawrzyniec Kaszub, Alexandre Merkulov and Wlodek Strupinski. Appl. Phys. Lett. 109, 011904 (2016)
J. Vac. Sci. Technol	SC Ultra	2016	SIMS depth profiling and topography studies of repetitive III–V trenches under low energy oxygen ion beam sputtering. Viktoriia Gorbenko, Franck Bassani, Alexandre Merkulov, Thierry Baron, Mickael Martin, Sylvain David and Jean-Paul Barnes. J. Vac. Sci. Technol. B 34, 03H131 (2016)
Journal of Nuclear Materials	SC Ultra	2016	Kr implantation into heavy ion irradiated monolithic UeMo/Al systems: SIMS and SEM investigations. T. Zweifel, N. Valle, C. Grygiel, I. Monnet, L. Beck, W. Petry (2016), Journal of Nuclear Materials, Volume 470, Pages 251-257.
Journal of mass spectrometry	SC Ultra	2015	Investigation of the depth-profiling capabilities of the Storing Matter technique. B. Kasel T. Wirtz. Journal of mass spectrometry (2015)
ACS Appl. Mater. Interfaces	SC Ultra	2015	Organo-Chlorinated Thin Films Deposited by Atmospheric Pressure Plasma-Enhanced Chemical Vapor Deposition for Adhesion Enhancement between Rubber and Zinc-Plated Steel Monofilaments. C. Vandenabeele, S. Bulou, R. Maurau, F. Siffer, T. Belmonte and P. Choquet. ACS Appl. Mater. Interfaces (2015), 7, 26, 14317–14327
SIMS Europe	SC Ultra	2014	Ion beam characterizations of plasma immersion ion implants for advanced nanoelectronic applications. M. Veillerot, F. Mazen, N. Payen, J.P. Barnes, F. Pierre (2014), SIMS Europe 2014, September 7-9, 2014
ACS Appl. Mater. Interfaces	SC Ultra	2014	Temperature-Dependent Wear Mechanisms for Magnetron-Sputtered AlTiTaN Hard Coatings. V. Khetan, N. Valle, D. Duday, C. Michotte, C. Mitterer, M-P Delplancke-Ogletree, and P. Choquet. ACS Appl. Mater. Interfaces (2014), 6, 17, 15403–15411
IIT	SC Ultra	2014	Characterization of arsenic PIII implants in FinFETs by LEXES, SIMS and STEM-EDX. Kim-Anh Bui-Thi Meura, Frank Torregrosa, Anne-Sophie Robbes, Seoyoun Choi, Alexandre Merkulov, Mona P. Moret, Julian Duchaine, Naoto Horiguchi, Letian Li, Christoph Mitterbauer (2014), 20th International Conference on Ion Implantation Technology (IIT), 2014
Surface and Interface Analysis	SC Ultra	2014	Cesium/Xenon dual beam sputtering in a Cameca instrument. R. Pureti, B.Douhard, D.Joris, A.Merkulov and W.Vandervorst. Surface and Interface Analysis. Volume 46, Issue S1, pages 25–30, November 2014
Surface and Interface Analysis	SC Ultra	2014	Si- useful yields measured in Si, SiC, Si3N4 and SiO2: comparison between the Strong Matter technique and SIMS. B.Kasel and T.Wirtz. Surface and Interface Analysis. Volume 46, Issue S1, pages 39–42, November 2014
Anal. Chem	SC Ultra	2014	Reduction of the SIMS Matrix Effect Using the Storing Matter Technique: A Case Study on Ti in Different Matrices. B. Kasel and T. Wirtz. Anal. Chem. (2014), 86, 8, 3750–3755
ACS Appl. Mater. Interfaces	SC Ultra	2014	Influence of Temperature on Oxidation Mechanisms of Fiber-Textured AlTiTaN Coatings. V. Khetan, N. Valle, D. Duday, C. Michotte, M-P Delplancke-Ogletree, and P. Choquet. ACS Appl. Mater. Interfaces (2014), 6, 6, 4115–4125
ACS Appl. Mater. Interfaces	SC Ultra	2013	Homogeneous Surface Oxidation of Organosilicates by Controlled Combustion of Adsorbed Fuels: A Facile Method for Low-Temperature Processing. Bob E. Feller, Vaughn R. Deline, John Bass, André Knoesen, and Robert D. Miller. ACS Appl. Mater. Interfaces (2013), 5, 18, 9075–9087
ACS Nano	SC Ultra	2013	Crystal-Facet-Dependent Metallization in Electrolyte-Gated Rutile TiO2 Single Crystals. T. D. Schladt, T. Graf, N. B. Aetukuri, M. Li, A Fantini, X Jiang, M. G. Samant, and S S. P. Parkin. ACS Nano (2013), 7, 9, 8074–8081
Surface Science Reports	SC Ultra	2013	Unravelling the secrets of Cs controlled secondary ion formation: Evidence of the dominance of site specific surface chemistry, alloying and ionic bonding. K. Wittmaack. Surface Science Reports. Volumn 68, Issue 1, pages 108–230, 1 March 2013
Anal. Chem	SC Ultra	2013	Ag-Organic Layered Samples for Optoelectronic Applications: Interface Width and Roughening Using a 500 eV Cs+ Probe in Dynamic Secondary Ion Mass Spectrometry. P. Philipp, Quyen K. Ngo, M. Shtein, J. Kieffer, and T. Wirtz. Anal. Chem. 2013, 85, 1, 381–388
Surface and Interface Analysis	SC Ultra	2013	The secondary ions emission from Si under low-energy Cs bombardment in a presence of oxygen. A. Merkulov. Surface and Interface Analysis. Volume 45, Issue 1, pages 90–92, January 2013
Surface and Interface Analysis	SC Ultra	2013	Application of extra-low impact energy SIMS and data reduction algorithm to USJ profiling. D. Kouzminov, A. Merkulov, E. Arevalo, H.-J. Grossmann. Surface and Interface Analysis. Volume 45, Issue 1, pages 345–347, January 2013

Surf. and Interface Analysis	SC Ultra	2012	Application of extra-low impact energy SIMS and data reduction algorithm to USJ profiling. D. Kouzminov, A. Merkulov, E. Arevalo, H.-J. Grossmann. Surf. and Interface Analysis, 5 Aug 2012
Surf. and Interface Analysis	SC Ultra	2012	The secondary ions emission from Si under low-energy Cs bombardment in a presence of oxygen. A. Merkulov. Surf. and Interface Analysis, 5 Aug 2012
Ultramicroscopy	SC Ultra	2011	Characteristics of cross-sectional atom probe analysis on semiconductor structures. S.Koelling, N. Innocenti, G.Hellings, M.Gilbert, A.K.Kambham, K. De Meyer, W. Vandervorst. Ultramicroscopy, Volume 111, Issue 6, (May 2011), Pages 540-545
Journal of Vacuum Science & Technology B	SC Ultra	2010	Experimental studies of dose retention and activation in fin field-effect-transistor-based structures. Jay Mody, Ray Duffy, Pierre Eyben, Jozefien Goossens, Alain Moussa, Wouter Polspoel, Bart Berghmans, M. J. H. van Dal, B. J. Pawlak, M. Kaiser, R. G. R. Weemaes, and Wilfried Vandervorst (2010), Journal of Vacuum Science & Technology B, Volume 28, Issue 1.
Journal of Vacuum Science & Technology B	SC Ultra	2010	Sputtering behavior and evolution of depth resolution upon low energy ion irradiation of GaAs. M.J.P. Hopstaken, M.S. Gordon, D. Pfeiffer, D.K. Sadana, T. Topuria, P.M. Rice, C. Gerl, M. Richter, C. Marchiori. Journal of Vacuum Science & Technology B: Microelectronics and Nanometer Structures. Volume 28, Issue 6, 1287, 18 November 2010
Analytical and Bioanalytical Chemistry	SC Ultra	2010	Depth profile characterization of ultra shallow junction implants. P. Hönicke, B. Beckhoff, M. Kolbe, D. Giubertoni, J. van den Berg & G. Pepponi. Analytical and Bioanalytical Chemistry volume 396, pages2825–2832(2010)
Journal of Vacuum Science & Technology B	SC Ultra	2010	Advanced SIMS quantification in the first few nm of B, P, and As Ultra Shallow Implants. A.Merkulov, P.Peres, J.Choi, F.Horreard, H-U.Ehrke, N. Loibl, M.Schuhmacher, Journal of Vacuum Science & Technology B. 28, C1C48 (2010) ; doi:10.1116/1.3225588
N/A	SC Ultra	2009	Chemical Erosion and Transport: Transport and Deposition of First Wall Impurities. Francesco Ghezzi (2009), CONSIGLIO NAZIONALE DELLE RICERCHE. TASK PWI-08-TA-06
Applied Surface Science	SC Ultra	2008	Long-term Reproducibility of Relative Sensitivity Factors Obtained with CAMECA Wf. D. Gui, ZX Xing, YH Huang, ZQ Mo, YN Hua, SP Zhao, LZ Cha. Applied Surface Science, Volume 255, Issue 4, Pages 1427–1429 (2008)
IIT	SC Ultra	2008	EXLE-SIMS: Dramatically Enhanced Accuracy for Dose Loss Metrology. W.Vandervorst, R.Vos, A.J.Salima, A.Merkulov, K. Nakajimac and K.Kimura. Proceedings of the 17th International Conference on Ion Implentation Technology, IIT 2008, Monterey, CA, USA. AIP Conf. Proc. Vol. 1066 (2008), 109-112
App. Surf. Science	SC Ultra	2008	Semiconductor profiling with sub-nm resolution: challenges and solutions. W.Vandervorst, App. Surf. Science 255 (2008) 805
App. Surf. Science	SC Ultra	2008	Roughness development in the depth profiling with 500eV O2 beam with the combination of oxygen flooding and sample rotation. D. Gui, Z.X.Xing, Y.H.Huang, Z.Q.Mo, Y.N.Hua, S.P.Zhao and L.Z.Cha, App. Surf. Science 255 (2008) 1433
App. Surf. Science	SC Ultra	2008	Depth profiling of ultra-thin oxynitride date dielectrics by using MCs2+ technique. D.Gui, Z.X.Xing, Y.H.Huang, Z.Q.Mo, Y.N.Hua, S.P.Zhao and L.Z.Cha (2008), App. Surf. Science, Volume 255, Issue 4, Pages 1437-1439. doi:10.1016/j.apsusc.2008.06.047
App. Surf. Science	SC Ultra	2008	Impurity measurement in silicon with D-SIMS and atom probe tomography. P.Ronsheim, App. Surf. Science 255 (2008) 1547.
App. Surf. Science	SC Ultra	2006	SIMS depth profiling of boron ultra shallow junctions using oblique O2 beam down to 150eV. M.Juhel, F.Laugier, D.Delille,C.Wyon, L.F.T.Kwakman and M.Hopstaken, App. Surf. Science 252 (2006), 7211
App. Surf. Science	SC Ultra	2006	Boron ultra low energy SIMS depth profiling improved by rotating stage. M.Bersani, D.Guibertoni, at al, App. Surf. Science 252 (2006) 7315
App. Surf. Science	SC Ultra	2006	Comparison between SIMS and MEIS techniques for the characterization of ultra shallow arsenic implants. M.Bersani, D.Guibertoni, et al, App. Surf. Science 252 (2006) 7214
App. Surf. Science	IMS Wf	2004	SIMS Depth Profiling of SiGe:C structures in test pattern areas using low energy Cs with a Cameca Wf , M.Juhel, F. Laugier, App. Surf. Science 231-232 (2004) 698
App. Surf. Science	SC Ultra	2004	Sputtered depth scales of multi-layered samples with in situ laser interferometry: arsenic diffusion in Si/SiGe layers. P.A.Ronsheim, R.Loesing and A.Mada, App. Surf. Science 231-232 (2004) 762
App. Surf. Science	SC Ultra	2004	Short-term and long-term RSF repeatability for CAMECA SC Ultra SIMS measurements. M. Barozzi, D. Giubertoni, M. Anderle and M. Bersani. App. Surf. Science 231-232 (2004) 768-771
App. Surf. Science	SC Ultra	2004	Toward accurate in-depth profiling of As and P ultra-shallow implants by SIMS. A. Merkulov, E. de Chambost, M. Schuhmacher and P. Peres. Oral presentation at SIMS XIV, San Diego, USA, Sep. 2003. Applied Surface Science 231–232 (2004) 640–644

App. Surf. Science	SC Ultra	2004	Accurate on-line depth calibration with laser interferometer during SIMS profiling experiment on the CAMECA IMS Wf instrument. O. Merkulova, A. Merkulov, M. Schuhmacher, and E. de Chambost. SIMS XIV, San Diego, USA, Sep. 2003. Applied Surface Science 231–232 (2004) 954–958
App. Surf. Science	SC Ultra	2004	Latest developments for the CAMECA ULE-SIMS instruments: IMS Wf and SC Ultra. E. de Chambost, A. Merkulov, P. Peres, B. Rasser, M. Schuhmacher. Poster for SIMS XIV, San Diego, USA, Sept 2003. Applied Surface Science 231–232 (2004) 949–953